3.3 V, 4 differential channel, 2 : 1 multiplexer/demultiplexer switch for PCI Express Gen3

Rev. 4 — 25 June 2012

Product data sheet

1. General description

CBTL04083A/B is a 4 differential channel, 2-to-1 multiplexer/demultiplexer switch for PCI Express Generation 3 (Gen3) applications. The CBTL04083A/B can switch four differential signals to one of two locations. Using a unique design technique, NXP has minimized the impedance of the switch such that the attenuation observed through the switch is negligible, and also minimized the channel-to-channel skew as well as channel-to-channel crosstalk, as required by the high-speed serial interface. CBTL04083A/B allows expansion of existing high speed ports for extremely low power.

The device's pin out are optimized to match different application layouts. CBTL04083A has input and output pins on the opposite of the package, and is suitable for edge connector(s) with different signal sources on the motherboard. CBTL04083B has outputs on both sides of the package, and the device can be placed between two connectors to multiplex differential signals from a controller. Please refer to <u>Section 8</u> for layout examples.

2. Features and benefits

- 4 differential channel, 2 : 1 multiplexer/demultiplexer
- High-speed signal switching for 8.0 Gbit/s PCIe Gen3 speed
- Low intra-pair skew: 5 ps typical
- Low inter-pair skew: 35 ps maximum
- High bandwidth:
 - ◆ -3 dB at 8.3 GHz for CBTL04083A
 - ◆ -3 dB at 8.0 GHz for CBTL04083B
- Low crosstalk: –29 dB at 4 GHz
- Low insertion loss
 - ◆ -0.5 dB at 100 MHz
 - ♦ –1.3 dB at 4 GHz
- Low off-state isolation: -20 dB at 4 GHz
- Low return loss: -14 dB at 4 GHz
- V_{DD} operating range: 3.3 V ± 10 %
- Dual shutdown pins for channel 0/1 and 2/3 independently to minimize power consumption
- ESD tolerance:
 - 2000 V HBM
 - 1000 V CDM
- HVQFN42 package



3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

3. Applications

- Routing of high-speed differential signals with low signal attenuation
 - PCIe Gen3
 - DisplayPort 1.2
 - USB 3.0
 - SATA 6 Gbit/s

4. Ordering information

Table 1.Ordering information

Type number	Package					
	Name	Description	Version			
CBTL04083ABS ^[1]	HVQFN42	plastic thermal enhanced very thin quad flat package; no leads; 42 terminals; body $3.5 \times 9 \times 0.85$ mm ^[3]	SOT1144-1			
CBTL04083BBS ^[2]	HVQFN42	plastic thermal enhanced very thin quad flat package; no leads; 42 terminals; body $3.5 \times 9 \times 0.85$ mm ^[3]	SOT1144-1			

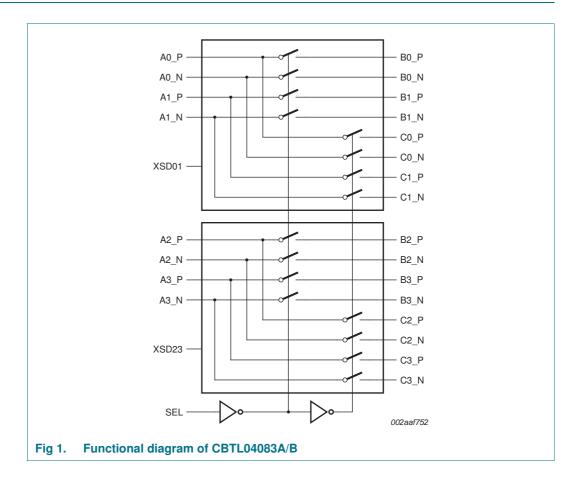
 CBTL04083ABS is available in tape and reel formats with different tape widths — 16 mm and 24 mm: For 16 mm tape width, order CBTL04083ABS 9352 941 24518 ("518" indicates 16 mm wide carrier tape). For 24 mm tape width, order CBTL04083ABS 9352 941 24558 ("558" indicates 24 mm wide carrier tape).

 [2] CBTL04083BBS is available in tape and reel formats with different tape widths — 16 mm and 24 mm: For 16 mm tape width, order CBTL04083BBS 9352 941 25518 ("518" indicates 16 mm wide carrier tape). For 24 mm tape width, order CBTL04083BBS 9352 941 25558 ("558" indicates 24 mm wide carrier tape).

[3] Total height after printed-circuit board mounting = 1.0 mm maximum.

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

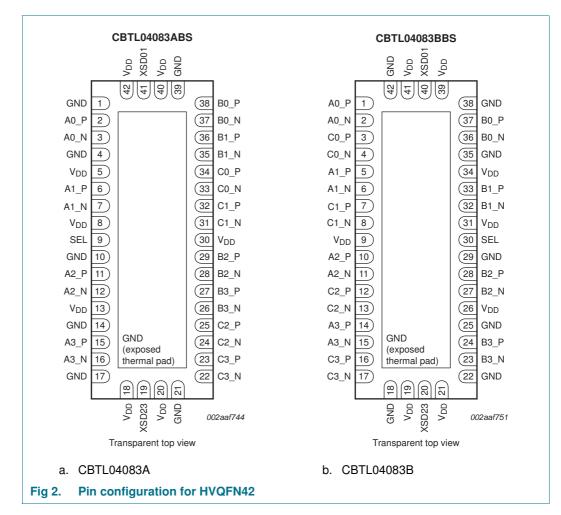
5. Functional diagram



3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

6. Pinning information

6.1 Pinning



6.2 Pin description

Table 2.Pin description

Type	Description
1/2	
I/O	channel 0, port A differential signal input/output
I/O	
I/O	channel 1, port A differential signal input/output
I/O	
I/O	channel 2, port A differential signal input/output
I/O	
I/O	channel 3, port A differential signal input/output
I/O	
	I/O I/O I/O I/O I/O I/O

CBTL04083A_CBTL04083B
Product data sheet

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3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

Symbol	Pin		Туре	Description		
	CBTL04083A	CBTL04083B				
B0_P	38	37	I/O	channel 0, port B differential signal input/output		
B0_N	37	36	I/O			
B1_P	36	33	I/O	channel 1, port B differential signal input/output		
B1_N	35	32	I/O			
B2_P	29	28	I/O	channel 2, port B differential signal input/output		
B2_N	28	27	I/O			
B3_P	27	24	I/O	channel 3, port B differential signal input/output		
B3_N	26	23	I/O			
C0_P	34	3	I/O	channel 0, port C differential signal input/output		
C0_N	33	4	I/O			
C1_P	32	7	I/O	channel 1, port C differential signal input/output		
C1_N	31	8	I/O			
C2_P	25	12	I/O	channel 2, port C differential signal input/output		
C2_N	24	13	I/O			
C3_P	23	16	I/O	channel 3, port C differential signal input/output		
C3_N	22	17	I/O			
SEL	9	30	CMOS single-ended input	operation mode select SEL = LOW: $A \rightarrow B$ SEL = HIGH: $A \rightarrow C$		
XSD01	41	40	CMOS single-ended input	Shutdown pin; should be driven LOW or connected to GND for normal operation. When HIGH, channel 0 and channel 1 are switched off (non-conducting high-impedance state), and supply current consumption is minimized.		
XSD23	19	20	CMOS single-ended input	Shutdown pin; should be driven LOW or connected to GND for normal operation. When HIGH, channel 2 and channel 3 are switched off (non-conducting high-impedance state), and supply current consumption is minimized.		
V _{DD}	5, 8, 13, 18, 20, 30, 40, 42	9, 19, 21, 26, 31, 34, 39, 41	power	positive supply voltage, 3.3 V \pm 10 %		
GND ^[1]	1, 4, 10, 14, 17, 21, 39, center pad	18, 22, 25, 29, 35, 38, 42, center pad	ground	supply ground		

[1] HVQFN32 package die supply ground is connected to both GND pins and exposed center pad. GND pins and the exposed center pad must be connected to supply ground for proper device operation. For enhanced thermal, electrical, and board level performance, the exposed pad needs to be soldered to the board using a corresponding thermal pad on the board and for proper heat conduction through the board, thermal vias need to be incorporated in the printed-circuit board in the thermal pad region.

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

7. Functional description

Refer to Figure 1 "Functional diagram of CBTL04083A/B".

7.1 Function selection

Table 3.Function selection

XSD01 XSD23 SEL Function HIGH - X An, Bn and Cn pins are high-Z, n = 0, 1 LOW - LOW An to Bn, n = 0, 1 LOW - HIGH An to Cn, n = 0, 1 - HIGH X An, Bn and Cn pins are high-Z, n = 2, 3 - LOW LOW An to Bn, n = 2, 3 - LOW HIGH An to Cn, n = 2, 3	X = Don't	X = Don't care.				
LOW-LOWAn to Bn, n = 0, 1LOW-HIGHAn to Cn, n = 0, 1-HIGHXAn, Bn and Cn pins are high-Z, n = 2, 3-LOWLOWAn to Bn, n = 2, 3	XSD01	XSD23	SEL	Function		
LOW-HIGHAn to Cn, n = 0, 1-HIGHXAn, Bn and Cn pins are high-Z, n = 2, 3-LOWLOWAn to Bn, n = 2, 3	HIGH	-	Х	An, Bn and Cn pins are high-Z, $n = 0, 1$		
-HIGHXAn, Bn and Cn pins are high-Z, n = 2, 3-LOWLOWAn to Bn, n = 2, 3	LOW	-	LOW	An to Bn, n = 0, 1		
- LOW LOW An to Bn, n = 2, 3	LOW	-	HIGH	An to Cn, n = 0, 1		
	-	HIGH	Х	An, Bn and Cn pins are high-Z, $n = 2, 3$		
- LOW HIGH An to Cn, n = 2, 3	-	LOW	LOW	An to Bn, n = 2, 3		
	-	LOW	HIGH	An to Cn, n = 2, 3		

7.2 Shutdown function

The CBTL04083A/B provides a shutdown function to minimize power consumption when the application is not active, but power to the CBTL04083A/B is provided. Pin XSD01 and XSD23 (active HIGH) puts channel 0/1 and 2/3 (respectively) in high-impedance state (non-conducting) while reducing current consumption to near-zero.

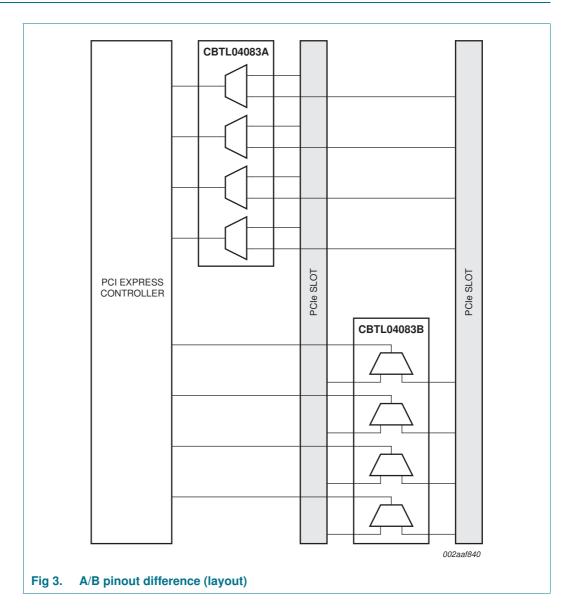
Table 4. Shutdown function XSD01 XSD23 Channel 0 Channel 1 Channel 2 HIGH high-Z high-Z LOW active active

LOW	-	active	active	-	-
-	HIGH	-	-	high-Z	high-Z
-	LOW	-	-	active	active

Channel 3

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

8. Application design-in information



3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

9. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DD}	supply voltage		-0.3	+4.6	V
T _{case}	case temperature		-40	+85	°C
V _{ESD}	electrostatic discharge voltage	HBM	<u>[1]</u> -	2000	V
		CDM	[2] _	1000	V

 Human Body Model: ANSI/EOS/ESD-S5.1-1994, standard for ESD sensitivity testing, Human Body Model -Component level; Electrostatic Discharge Association, Rome, NY, USA.

 Charged Device Model: ANSI/EOS/ESD-S5.3-1-1999, standard for ESD sensitivity testing, Charged Device Model - Component level; Electrostatic Discharge Association, Rome, NY, USA.

10. Recommended operating conditions

Table 6.	Recommended operating conditions					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DD}	supply voltage		3.0	3.3	3.6	V
VI	input voltage		-	-	V_{DD}	V
T _{amb}	ambient temperature	operating in free air	-40	-	+85	°C

11. Static characteristics

Table 7. Static characteristics

 V_{DD} = 3.3 V ± 10 %; T_{amb} = -40 °C to +85 °C; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ <mark>[1]</mark>	Max	Unit
I _{DD}	supply current	operating mode (both XSD01 and XSD23 are LOW); $V_{\text{DD}} = \text{max}.$	-	2.7	5	mA
		shutdown mode (both XSD01 and XSD23 are HIGH); $V_{\text{DD}} = \text{max}.$	-	-	1	μA
I _{IH}	HIGH-level input current	$V_{DD} = max.; V_I = V_{DD}$	-	-	<u>+5[2]</u>	μA
IIL	LOW-level input current	$V_{DD} = max.; V_I = GND$	-	-	<u>+5[2]</u>	μA
V _{IH}	HIGH-level input voltage	SEL, XSD01, XSD23 pins	$0.65V_{DD}$	-	-	V
V _{IL}	LOW-level input voltage	SEL, XSD01, XSD23 pins	-0.5	-	$0.35V_{DD}$	V
VI	input voltage	differential pins	-	-	2.4	V
		SEL, XSD01, XSD23 pins	-	-	V_{DD}	V
V _{IC}	common-mode input voltage		0	-	2	V
V _{ID}	differential input voltage	peak-to-peak	-	-	1.6	V

[1] Typical values are at V_DD = 3.3 V, T_{amb} = 25 °C, and maximum loading.

[2] Input leakage current is $\pm 50 \ \mu$ A if differential pairs are pulled to HIGH and LOW.

CBTL04083A_CBTL04083B
Product data sheet

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

12. Dynamic characteristics

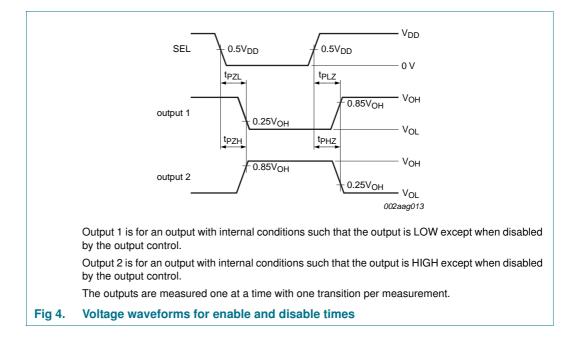
Table 8. Dynamic characteristics

 V_{DD} = 3.3 V \pm 10 %; T_{amb} = -40 °C to +85 °C; unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ <mark>[1]</mark>	Max	Unit
DDNEXT	differential near-end crosstalk	adjacent channels are ON				
		f = 4 GHz	-	-29	-	dB
		f = 100 MHz	-	-45	-	dB
DDIL	differential insertion loss	channel is OFF				
		f = 4 GHz	-	-20	-	dB
		f = 100 MHz	-	-50	-	dB
		channel is ON				
		f = 4 GHz	-	-1.3	-	dB
		f = 100 MHz	-	-0.5	-	dB
DDRL	differential return loss	f = 4 GHz		-14		dB
		f = 100 MHz	-	-24	-	dB
R _{on}	ON-state resistance	$V_{DD} = 3.3 \text{ V}; \text{ V}_{I} = 2 \text{ V}; \text{ I}_{I} = 19 \text{ mA}$	-	6	-	Ω
C _{io(on)}	on-state input/output capacitance		-	1.5	-	pF
B_3dB	–3 dB bandwidth	CBTL04083A	-	8.3	-	GHz
		CBTL04083B	-	8.0	-	GHz
t _{PD}	propagation delay	from left-side port to right-side port, or vice versa	-	60	-	ps
Switching	g characteristics					
t _{startup}	start-up time	supply voltage valid or XSD01/XSD23 going LOW to channel specified operating characteristics	-	-	10	ms
t _{PZH}	OFF-state to HIGH propagation delay		-	-	300	ns
t _{PZL}	OFF-state to LOW propagation delay		-	-	70	ns
t _{PHZ}	HIGH to OFF-state propagation delay		-	-	50	ns
t _{PLZ}	LOW to OFF-state propagation delay		-	-	50	ns
t _{sk(dif)}	differential skew time	intra-pair	-	5	-	ps
t _{sk}	skew time	inter-pair	-	-	35	ps

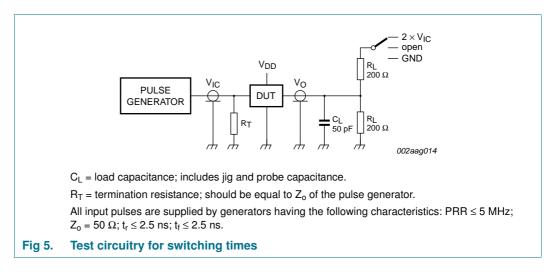
[1] Typical values are at V_{DD} = 3.3 V; T_{amb} = 25 °C, and maximum loading.

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3



3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

13. Test information



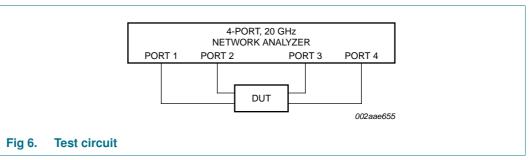


Table 9. Test data

Test	Load		Switch
	CL	RL	-
t_{PLZ} , t_{PZL} (output on B side)	50 pF	200 Ω	$2 \times V_{IC}$
t _{PHZ} , t _{PZH} (output on B side)	50 pF	200 Ω	GND
t _{PD}	-	200 Ω	open

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CBTL04083A; CBTL04083B

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

14. Package outline

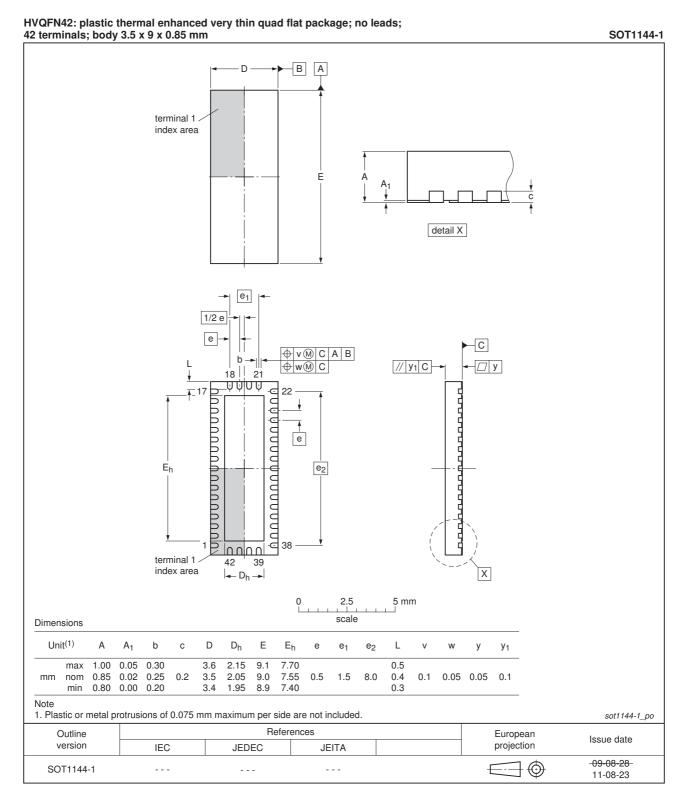


Fig 7. Package outline SOT1144-1 (HVQFN42)

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3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

15. Soldering of SMD packages

This text provides a very brief insight into a complex technology. A more in-depth account of soldering ICs can be found in Application Note *AN10365 "Surface mount reflow soldering description"*.

15.1 Introduction to soldering

Soldering is one of the most common methods through which packages are attached to Printed Circuit Boards (PCBs), to form electrical circuits. The soldered joint provides both the mechanical and the electrical connection. There is no single soldering method that is ideal for all IC packages. Wave soldering is often preferred when through-hole and Surface Mount Devices (SMDs) are mixed on one printed wiring board; however, it is not suitable for fine pitch SMDs. Reflow soldering is ideal for the small pitches and high densities that come with increased miniaturization.

15.2 Wave and reflow soldering

Wave soldering is a joining technology in which the joints are made by solder coming from a standing wave of liquid solder. The wave soldering process is suitable for the following:

- Through-hole components
- Leaded or leadless SMDs, which are glued to the surface of the printed circuit board

Not all SMDs can be wave soldered. Packages with solder balls, and some leadless packages which have solder lands underneath the body, cannot be wave soldered. Also, leaded SMDs with leads having a pitch smaller than ~0.6 mm cannot be wave soldered, due to an increased probability of bridging.

The reflow soldering process involves applying solder paste to a board, followed by component placement and exposure to a temperature profile. Leaded packages, packages with solder balls, and leadless packages are all reflow solderable.

Key characteristics in both wave and reflow soldering are:

- · Board specifications, including the board finish, solder masks and vias
- · Package footprints, including solder thieves and orientation
- · The moisture sensitivity level of the packages
- Package placement
- Inspection and repair
- Lead-free soldering versus SnPb soldering

15.3 Wave soldering

Key characteristics in wave soldering are:

- Process issues, such as application of adhesive and flux, clinching of leads, board transport, the solder wave parameters, and the time during which components are exposed to the wave
- · Solder bath specifications, including temperature and impurities

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

15.4 Reflow soldering

Key characteristics in reflow soldering are:

- Lead-free versus SnPb soldering; note that a lead-free reflow process usually leads to higher minimum peak temperatures (see <u>Figure 8</u>) than a SnPb process, thus reducing the process window
- Solder paste printing issues including smearing, release, and adjusting the process window for a mix of large and small components on one board
- Reflow temperature profile; this profile includes preheat, reflow (in which the board is heated to the peak temperature) and cooling down. It is imperative that the peak temperature is high enough for the solder to make reliable solder joints (a solder paste characteristic). In addition, the peak temperature must be low enough that the packages and/or boards are not damaged. The peak temperature of the package depends on package thickness and volume and is classified in accordance with Table 10 and 11

Table 10. SnPb eutectic process (from J-STD-020C)

Package thickness (mm)	Package reflow temperature (°C) Volume (mm ³)				
	< 350	≥ 350			
< 2.5	235	220			
≥ 2.5	220	220			

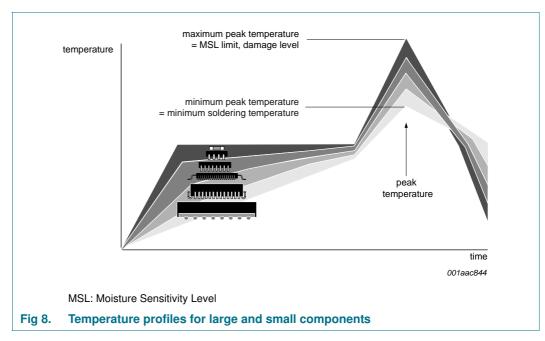
Table 11. Lead-free process (from J-STD-020C)

Package thickness (mm)	Package reflow temperature (°C) Volume (mm ³)				
	< 350 350 to 2000 > 2000				
< 1.6	260	260	260		
1.6 to 2.5	260	250	245		
> 2.5	250	245	245		

Moisture sensitivity precautions, as indicated on the packing, must be respected at all times.

Studies have shown that small packages reach higher temperatures during reflow soldering, see Figure 8.

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3



For further information on temperature profiles, refer to Application Note *AN10365 "Surface mount reflow soldering description"*.

16. Abbreviations

Table 12. Ab	breviations
Acronym	Description
CDM	Charged-Device Model
CMOS	Complementary Metal-Oxide Semiconductor
DUT	Device Under Test
ESD	ElectroStatic Discharge
HBM	Human Body Model
I/O	Input/Output
PCI	Peripheral Component Interconnect
PCle	PCI express
PRR	Pulse Repetition Rate
SATA	Serial Advanced Technology Attachment
USB	Universal Serial Bus

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

17. Revision history

Table 13.Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
CBTL04083A_CBTL04083B v.4	20120625	Product data sheet	-	CBTL04083A_CBTL04083B v.3
Modifications:	Section 2	Features and benefits		
	– sixth bu	ullet changed from "-3	5 dB" to "–29 dB"	
	 ninth be 	ullet changed from "-2	0 dB" to "–14 dB"	
	• <u>Table 1 "O</u>	rdering information":		
	 added 	(new) <u>Table note [1]</u>		
	 added 	(new) <u>Table note [2]</u>		
	 <u>Table 2 "P</u> "ground" 	in description", last tab	le row: GND "Type	" changed from "power" to
	 <u>Table 8 "D</u> 	ynamic characteristics	·	
	– DDNEX	KT (condition "f = 4 GH	z") typical value cł	nanged from "–35 dB" to "–29 dB"
	– DDRL	(condition "f = 4 GHz")	typical value chan	ged from "–20 dB" to "–14 dB"
	– DDRL	(condition "f = 100 MH:	z") typical value ch	anged from "-25 dB" to "-24 dB"
CBTL04083A_CBTL04083B v.3	20110824	Product data sheet	-	CBTL04083A_CBTL04083B v.2
CBTL04083A_CBTL04083B v.2	20110524	Product data sheet	-	CBTL04083A_CBTL04083B v.1
CBTL04083A_CBTL04083B v.1	20110228	Product data sheet	-	-

3.3 V, 4 differential channel, 2 : 1 MUX/deMUX switch for PCIe Gen3

18. Legal information

18.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

[3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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CBTL04083A; CBTL04083B

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20. Contents

1	General description 1
2	Features and benefits 1
3	Applications 2
4	Ordering information 2
5	Functional diagram 3
6	Pinning information 4
6.1	Pinning
6.2	Pin description 4
7	Functional description 6
7.1	Function selection 6
7.2	Shutdown function 6
8	Application design-in information 7
9	Limiting values
10	Recommended operating conditions 8
11	Static characteristics 8
12	Dynamic characteristics 9
13	Test information 11
14	Package outline 12
15	Soldering of SMD packages 13
15.1	Introduction to soldering
15.2	Wave and reflow soldering 13
15.3	Wave soldering 13
15.4	Reflow soldering 14
16	Abbreviations 15
17	Revision history 16
18	Legal information
18.1	Data sheet status 17
18.2	Definitions 17
18.3	Disclaimers
18.4	Trademarks
19	Contact information 18
20	Contents 19

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Date of release: 25 June 2012 Document identifier: CBTL04083A_CBTL04083B